

# 2303081427 Package Materials Update for Si4x5x & Si4x6x in ASECL

PCN Issue Date: Mar 08, 2023 Effective Date: Jun 14, 2023

PCN Type: Assembly

#### **Description of Change**

Silicon Labs is pleased to announce the successful qualification of BOM (Bill of Materials) for Si4x5x & Si4x6x, manufactured in ASECL. Details of BOM change are mentioned in the table below. ASECL is an existing Assembly, Test & Shipping site for this product.

As of the effective date of this PCN, Silicon Labs will fulfill orders from either the existing or new BOM. Once the current BOM is depleted, orders will be fulfilled from the new BOM.

вом	Current BOM	New BOM
Mold Compound	Sumitomo EME-G700LY	Sumitomo EME-G700LA
Wire	PdCu, 0.8mil	AuPdCu, 0.8mil

## **Reason for Change**

New BOM for supply continuity.

#### Impact on Form, Fit, Function, Quality, Reliability

No impact on Form, Fit, Function, Quality, Reliability.

## **Product Identification**

This notification includes both standard and customer-specific part numbers. An asterisk \* represents a number or letter (one or more) in a customer-specific part number.

SI4463-C2A-\*M0

SI4463-C2A-\*MØR SI4463M\*CGM SI4463M\*CGMR SI4467-A2A-IM SI4467-A2A-IMR SI4468-A2A-IM SI4468-A2A-IMR

Last Date of Unchanged Product: Jun 14, 2023

## **Qualification Samples**

Available upon request.

#### **Customer Response**

Lack of acknowledgment of the PCN within 30 days constitutes acceptance of the change, Ref. JEDEC-J-STD-046.

To request further data or inquire about this notification, please contact your Silicon Labs sales representative. A list of Silicon Labs sales representatives is available at <a href="http://www.silabs.com">http://www.silabs.com</a>.

Customers may approve early PCN acceptance by emailing approval, along with PCN # to PCNEarlyAcceptance@silabs.com

#### **User Registration**

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### **Qualification Data**

Qualification report is attached.



# Si4xxx-C2A / Si446x-A2A Qualification Report

Part Rev C2, TSM	Part Rev C2, TSMC Fabrication, ASECL 20-QFN-4x4 Assembly except as noted								
Test Name	Test Condition	Qualification	Lot ID or Start	Fail/Pass or End	Notes	Summary	Status		
	elerated Environment Stress	Tests							
HAST	JA110		Q035030	0/80	1				
	130°C, 85%RH	3 lots, N=>77	Q035235	0/80	1	6 lots	Pass		
	Vcc=3.8V, 96 hours		Q035240	0/79	1	0/479			
			Q049640	0/80	1, 6				
			Q049641	0/80	1, 6				
			Q049642	0/80	1, 6				
UHAST	JA110		Q035032	0/80	1				
	130°C, 85%RH	3 lots, N=>77	Q035237	0/80	1	6 lots	Pass		
	96 hours		Q035238	0/80	1	0/480			
			Q049808	0/80	1, 2, 6				
			Q049809	0/80	1, 2, 6				
			Q049810	0/80	1, 2, 6				
Temp Cycle	JA104		Q035031	0/80	1				
	Cond C: -65°C to 150°C		Q035236	0/80	1				
	500 cycles	3 lots, N=>77	Q035239	0/80	1	12 lots	Pass		

		I	Q035279	0/90	1, 2	0/1045	
			Q035280	0/90	1, 2		
			Q035281	0/90	1, 2		
			Q049662	0/80	1, 6		
			Q049663	0/80	1, 6		
			Q049664	0/80	1, 6		
			Q049807	0/98	1, 2, 6		
			Q049806	0/100	1, 2, 6		
			Q049805	0/97	1, 2, 6		
HTSL	JA103		Q035033	0/78	1		
	150°C, 1000hr	1 lot, N=>45	Q035241	0/48	1	3 lots	Pass
			Q035242	0/49	1	0/175	
	Accelerated Environment Stres	s Tests (UNISEM)	Q035242	0/49	1	0/175	
Test Group A -	Accelerated Environment Stres	s Tests (UNISEM)	Q035242 Q049726	0/49	1	0/175	
		s Tests (UNISEM) 3 lots, N=>77			1 1	0/175 3 lots	Pass
	JA110		Q049726	0/80			Pass
HAST	JA110 130°C, 85%RH		Q049726 Q049727	0/80	1	3 lots	Pass
HAST	JA110 130°C, 85%RH Vcc=3.8V, 96 hours		Q049726 Q049727 Q049728	0/80 0/80 0/80	1	3 lots	Pass
HAST	JA110 130°C, 85%RH Vcc=3.8V, 96 hours JA110	3 lots, N=>77	Q049726 Q049727 Q049728 Q049749	0/80 0/80 0/80 0/80	1 1	3 lots	Pass
	JA110 130°C, 85%RH Vcc=3.8V, 96 hours JA110 130°C, 85%RH	3 lots, N=>77	Q049726 Q049727 Q049728 Q049749 Q049752	0/80 0/80 0/80 0/80 0/80	1 1 1 1	3 lots 0/240	
HAST	JA110 130°C, 85%RH Vcc=3.8V, 96 hours JA110 130°C, 85%RH	3 lots, N=>77	Q049726 Q049727 Q049728 Q049749 Q049752 Q049754	0/80 0/80 0/80 0/80 0/80 0/80	1 1 1 1 1	3 lots 0/240 6 lots	
HAST	JA110 130°C, 85%RH Vcc=3.8V, 96 hours JA110 130°C, 85%RH	3 lots, N=>77	Q049726 Q049727 Q049728 Q049749 Q049752 Q049754 Q049842	0/80 0/80 0/80 0/80 0/80 0/80 0/90	1 1 1 1 1 1,2	3 lots 0/240 6 lots	

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# Si4xxx-C2A / Si446x-A2A Qualification Report

Part Rev C2, TS	SMC Fabrication, ASECL 20-	JFN-4x4 Assembl					
Test Name	Test Condition	Qualification	Lot ID or Start	Fail/Pass or End	Notes	Summary	Status
	Cond C: -65°C to 150°C		Q049851	0/85	1		
	500 cycles	3 lots, N=>77	Q049852	0/84	1	6 lots	Pass
			Q049843	0/94	1, 2	0/538	
			Q049846	0/95	1, 2		
			Q049849	0/95	1, 2		
HTSL	JA103		Q049925	0/80	1		
	150°C, 1000hr	1 lot, N=>45	Q049926	0/80	1		
			Q049927	0/78	1	6 lots	Pass
			Q050053	0/90	1, 2	0/508	
			Q050054	0/90	1, 2		
			Q050055	0/90	1, 2		
Test Group B - A	Accelerated Lifetime Simulation	Tests					
HTOL	JA108		Q035137	0/85			

	T <sub>J</sub> ≥ 125°C, Dynamic	3 lots, N=>77	Q035721	0/81		3 lots	Pass
	Vcc=3.8V, 1000 hours		Q035945	0/83		0/249	
LTOL	JA108						
	-10°C, Dynamic	1 lot, N=>77	Q030413	0/80		1 lot	Pass
	Vcc=3.8V, 1000 hours					0/80	
ELFR	AEC-Q100-008		Q035612	0/814			
	T <sub>J</sub> ≥ 125°C, Dynamic	3 lots, N=>800	Q035671	0/818		3 lots	Pass
	Vcc=3.8V, 48 hours		Q035944	0/812		0/2444	
Test Group C - Pac	kage Assembly Integrity Tes	sts					
Wire Bond Shear	AEC-Q100-001		630749	0/30			
		5 units, N=>30	630750	0/30		9 lots	Pas
			634080	0/30		0/270	
			1162036	0/30	6		
			1162307	0/30	6		
			1162038	0/30	6		
			1162040	0/30	2, 6		
			1162041	0/30	2, 6		
			1175623	0/30	2, 6		
Wire Bond Pull	M-STD-883		630749	0/30			
	Performed post-TC	5 units, N=>30	630750	0/30		9 lots	Pass
			634080	0/30		0/270	
			Q050011	0/30	6		
			Q050012	0/30	6		
			Q050013	0/30	6		
			Q050015	0/30	2, 6		

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## Si4xxx-C2A / Si446x-A2A Qualification Report

Part Rev C2, TSMC Fabrication, ASECL 20-QFN-4x4 Assembly except as noted									
Test Name	Test Condition	Qualification	Lot ID or Start	Fail/Pass or End	Notes	Summary	Status		
			Q050016	0/30	2, 6				
			Q050017	0/30	2, 6				
Physical Dimensions	JB100		630749	0/30					
		3 lots, N=>10	630750	0/30		9 lots	Pass		
			634080	0/30		0/270			
			1162036	0/30	6				
			1162307	0/30	6				
			1162038	0/30	6				
			1162040	0/30	2, 6				
			1162041	0/30	2, 6				

			1175623	0/30	2, 6		
Solderability	J-STD-002		630749	0/10			
		1 lot, N=>15	630750	0/10		9 lots	Pass
			634080	0/10		0/90	
			1162036	0/10	6		
			1162307	0/10	6		
			1162038	0/10	6		
			1162040	0/10	2, 6		
			1162041	0/10	2, 6		
			1175623	0/10	2, 6		
-	age Assembly Integrity Tests	(UNISEM)					
Wire Bond Shear	AEC-Q100-001		1166864	0/30			
		5 units, N=>30	1166867	0/30	2	2 lots	Pass
						0/60	
Wire Bond Pull	M-STD-883		Q049943	0/30			
	Performed post-TC	5 units, N=>30	Q050052	0/30	2	2 lots	Pass
						0/60	
Physical Dimensions	JB100		1166864	0/30			
		3 lots, N=>10	1166867	0/30	2	2 lots	Pass
						0/60	
Solderability	J-STD-002		1166864	0/10			
		1 lot, N=>15	1166867	0/10	2	2 lots	Pass
						0/20	
Test Group E - Electr	rical Verification						
ESD-HBM	AEC-Q100-002		Q035921		5		±2 kV
		1 lot, N=>3	Q035948		4		±2 kV
			Q035953		2, 3		±2 kV
ESD-MM	AEC-Q100-003		Q035927		5		±200 V

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# Si4xxx-C2A / Si446x-A2A Qualification Report

Part Rev C2, TSMC Fabrication, ASECL 20-QFN-4x4 Assembly except as noted								
Test Name	Test Condition	Qualification	Lot ID or Start	Fail/Pass or End	Notes	Summary	Status	
		1 lot, N=>3	Q035949		4		±150 V	
			Q035954		2, 3		±150 V	
ESD-CDM	AEC-Q100-011		Q035919		5		±500 V	
		1 lot, N=>3	Q036260		4		±400 V	
			Q035955		3		±500 V	
			Q035955		2		±500 V	
Latch Up	AEC-Q100-004		Q035947	25C	5			

Gate Leakage  Electromagnetic  Compatibility	AEC-Q100-006 SAE J1752	1 lot, N=>6 1 lot, N=>1	Q035959 Q035960	0/6		1 lot	Pass
			Q035956 Q035957	25C 125C	2, 3 2, 3		
			Q035952	125C	4		
	±200mA Overvoltage = 5.7V	1 lot, N=>6	Q035946 Q035951	125C 25C	5 4		Pass

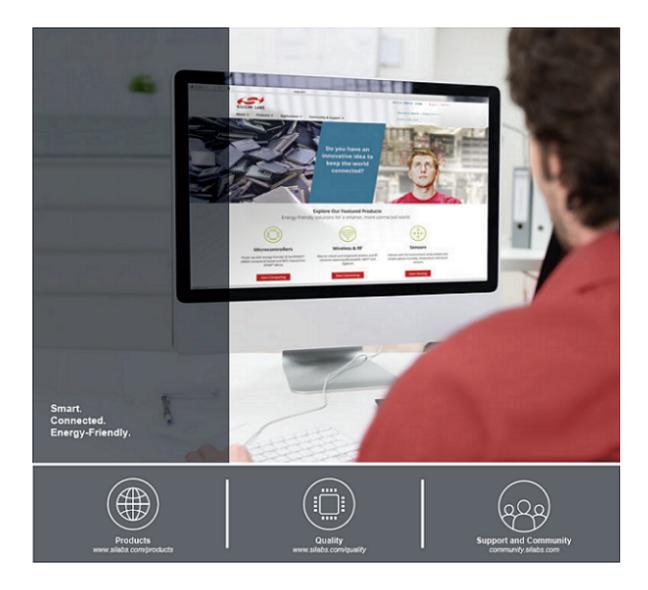
#### Notes:

- 1. Parts are Pre-conditioned at MSL1/260°C
- 2. Qualification applies to Si4x5x (3x3 QFN package)
- 3. Qualification applies to Si4461
- 4. Qualification applies to Si4060, Si4460, Si4467
- 5. Qualification applies to Si4063, Si4362, Si4438, Si4463, Si4468
- 6. Qualification applies to streamline BOM update at ASECL

	This report applies to the following part numbers:							
SI4055-B1A-FM	SI4355-B1A-FM	SI4438-B1C-FDI	SI4460-B1B-FDI					
SI4055-C2A-GM	SI4355-C2A-GM	SI4438-B1C-FM	SI4460-B1B-FM					
SI4060-B1B-FM	SI4356-B1A-FM	SI4438-C2A-GM	SI4460-C2A-GM					
SI4060-C2A-GM	SI4356-C2A-GM	SI4455-B1A-FM	SI4461-B1B-FM					
SI4063-B1B-FM	SI4362-B1B-FM	SI4455-C2A-GM	SI4461-C2A-GM					
SI4063-C2A-GM	SI4362-C2A-GM		SI4463-B1B-FM					
		SI4467-A2A-IM	SI4463-C2A-GM					
		SI4468-A2A-IM	SI4464-B1B-FM					

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